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Influence of distortions of recorded diffraction patterns on strain analysis by nano-beam electron diffraction

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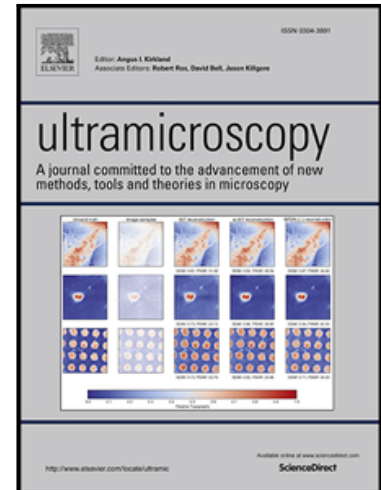
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Highlights

- measurement and correction of diffraction pattern distortions
- influence of diffraction pattern distortions on measurements of strain
- influence of diffraction pattern distortions on measurements of tetragonal distortions
- comparison of two techniques for the detection of diffraction disc positions

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